

LT - SPM

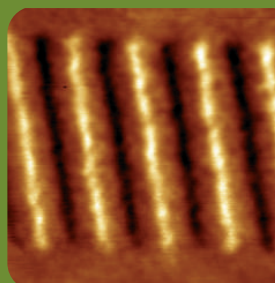
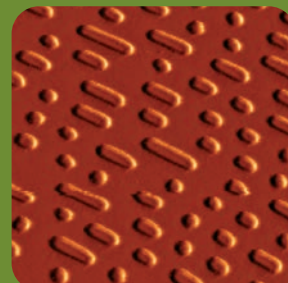
Low Temperature Scanning Probe Microscope



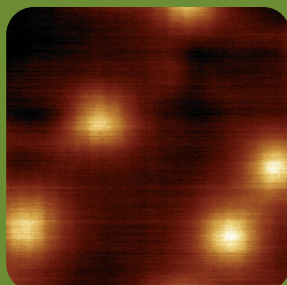


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Low Temperature Scanning Probe Microscope

MFM Image of
Hard Disk, 77 K

AFM Image of
DVD Surface, 4.2 K

STM Image of
Gold on Mica, 77 K


Vortices in BSCCO, 77 K


AFM (Phase) Image of
Calibration Grating, 4.2 K

SHPM Image of
NIST Calibration Sample, 77 K


System Specifications

Imaging Modes	: SHPM, STM, AFM, MFM, EFM, SNOM (in development)		
Scan Size Head	: Large Area Scan Head	: Standart Scan Head	: Small Area Scan
	150 x 150 μm @ 300 K 36 x 36 μm @ 77 K 18 x 18 μm @ 4.2 K	52 x 52 μm @ 300K 14 x 14 μm @ 77 K 6 x 6 μm @ 4.2 K	8 x 8 μm @ 300 K 3.5 x 3.5 μm @ 77 K 1.5 x 1.5 μm @ 4.2 K
Z Range	: 7.0 μm @ 300 K 1.8 μm @ 77 K 0.8 μm @ 4.2 K	4.8 μm @ 300 K 1.2 μm @ 77 K 0.5 μm @ 4.2 K	2.4 μm @ 300 K 0.6 μm @ 77K 0.25 μm @ 4.2K
Head Dimensions	: 23.6 mm OD x 125 mm or 25.4 mm OD x 100 mm		
Sample Approach	: Stick-slip type; 10 mm Z, Φ 3 mm XY range with 50 - 800 nm step size		
Sample Size	: 15 x 15 x 5 mm maximum		
Temperature Range	: 1.0 K - 300 K (Limited by the cryogenic equipment)		
Magnetic Field	: >16 T		

Suitable cryostats are also available

Software upgrades are free for lifetime

Note: Specifications are subject to change without notice.